

ID243E01

4MB Flash Memory Card

(Model No.: ID243E01)

Spec No.: EL093031
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application areas, be sure to observe the precautions given in Paragraph (2). Never use the products for the equipment listed in Paragraph (3).

- Office electronics
- Instrumentation and measuring equipment
- Machine tools
- Audiovisual equipment
- Home appliances
- Communication equipment other than for trunk lines

(2) Those contemplating using the products covered herein for the following equipment which demands high reliability, should first contact a sales representative of the company and then accept responsibility for incorporating into the design fail-safe operation, redundancy, and other appropriate measures for ensuring reliability and safety of the equipment and the overall system.

- Control and safety devices for airplanes, trains, automobiles, and other transportation equipment
- Mainframe computers
- Traffic control systems
- Gas leak detectors and automatic cutoff devices
- Rescue and security equipment
- Other safety devices and safety equipment, etc.

(3) Do not use the products covered herein for the following equipment which demands extremely high performance in terms of functionality, reliability, or accuracy.

- Aerospace equipment
- Communications equipment for trunk lines
- Control equipment for the nuclear power industry
- Medical equipment related to life support, etc.

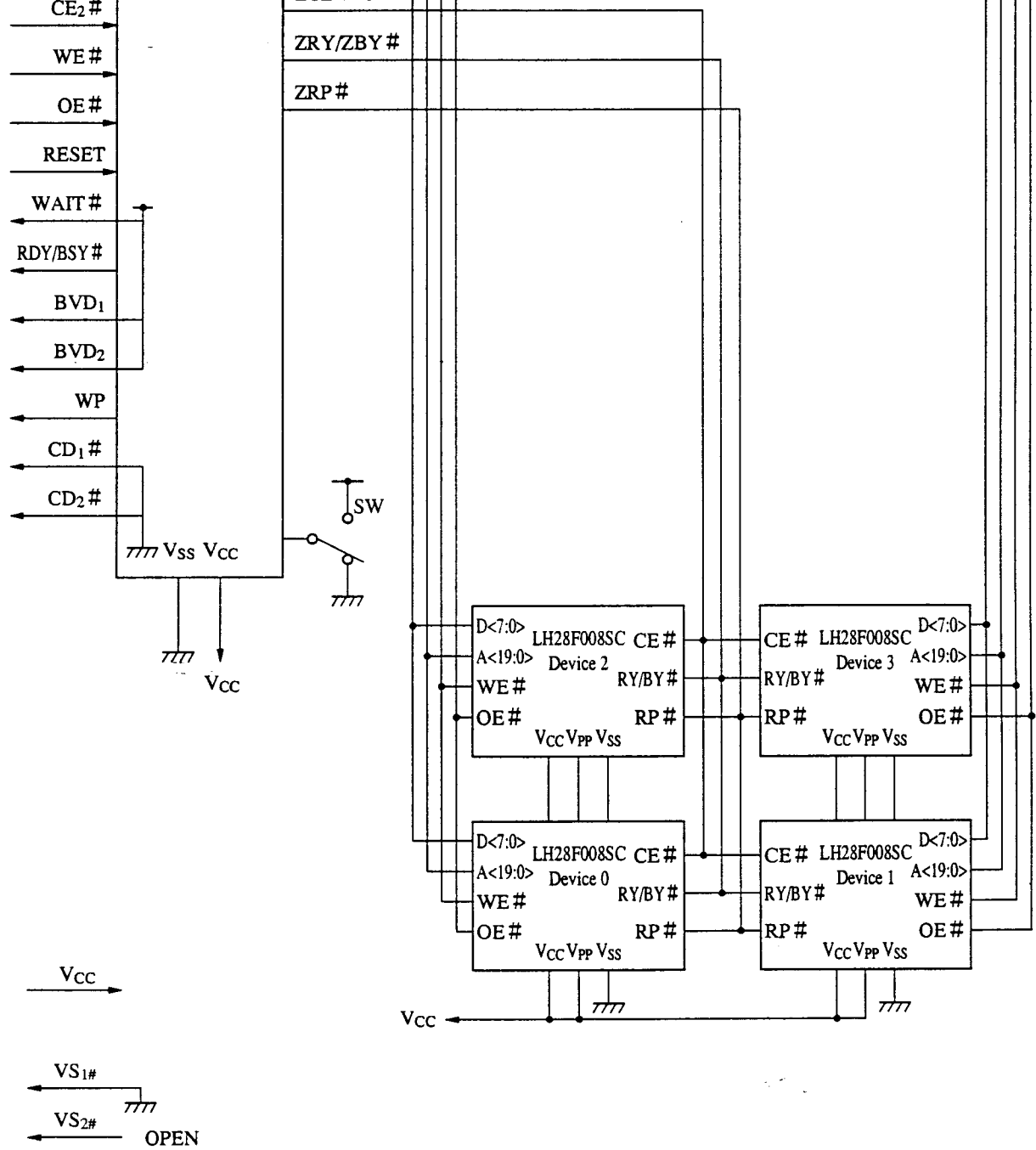
(4) Please direct all queries and comments regarding the interpretation of the above three Paragraphs to a sales representative of the company.

- Please direct all queries regarding the products covered herein to a sales representative of the company.

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|------|--|--|
| 2.2 | Memory Capacity | |
| | Main Memory | 2M words × 16 bits (4M words × 8 bits) |
| 2.3 | Supply Voltage | 5.0V ± 5% or 3.3V ± 0.3V |
| 2.4 | Erase Unit | 64K word Blocks |
| 2.5 | Program/Erase Cycles | 100,000 cycles per Block |
| 2.6 | Interface | Parallel I/O Interface |
| 2.7 | Function Table | See Function Table in page. 10 |
| 2.8 | External Dimensions | 54.0 × 85.6 × 3.3 mm |
| 2.9 | Pin Connections | See Pin Connections in page. 5 |
| 2.10 | Type of Connector | Conforms to PCMCIA Rel. 2.0 Card Use Connector
(Card connector: JC20-J68S-NB3 JAE or FCN-568J068-G/0 Fujitsu) |
| 2.11 | Average Weight | 30g |
| 2.12 | Operating
Temp. Range | 0 to 60°C |
| 2.13 | Storage
Temp. Range | -20 to 65°C |
| 2.14 | External Appearance | External appearance shall be free of any dirt, cratches and abnormalities that could adversely affect sales. |
| 2.15 | Manufacturer's Code | The manufacturer's code shall be printed on the memory card directly or on the seal which is then attached to the memory card. |
| 2.16 | Brand Name | The user's brand name will used. |
| 2.17 | Not designed for rated radiation hardened. | |



7	CE ₁ #	I	Card Enable 1	LOW	41	D ₁₅	I/O	Data Bit 15	
8	A ₁₀	I	Address Bit 10		42	CE ₂ #	I	Card Enable 2	LOW
9	OE#	I	Output Enable	LOW	43	VS ₁ #	O	Voltage Sense 1	LOW
10	A ₁₁	I	Address Bit 11		44	RFU		Reserved	
11	A ₉	I	Address Bit 9		45	RFU		Reserved	
12	A ₈	I	Address Bit 8		46	A ₁₇	I	Address Bit 17	
13	A ₁₃	I	Address Bit 13		47	A ₁₈	I	Address Bit 18	
14	A ₁₄	I	Address Bit 14		48	A ₁₉	I	Address Bit 19	
15	WE#	I	Write Enable	LOW	49	A ₂₀	I	Address Bit 20	
16	RDY/BSY#	O	Ready/Busy	LOW	50	A ₂₁	I	Address Bit 21	
17	V _{CC}		Supply Voltage		51	V _{CC}		Supply Voltage	
18	V _{PP1}		Supply Voltage	N.C.	52	V _{PP2}		Supply Voltage	N.C.
19	A ₁₆	I	Address Bit 16		53	A ₂₂	I	Address Bit 22	N.C.
20	A ₁₅	I	Address Bit 15		54	A ₂₃	I	Address Bit 23	N.C.
21	A ₁₂	I	Address Bit 12		55	A ₂₄	I	Address Bit 24	N.C.
22	A ₇	I	Address Bit 7		56	A ₂₅	I	Address Bit 25	N.C.
23	A ₆	I	Address Bit 6		57	VS ₂ #	O	Voltage Sense 2	N.C.
24	A ₅	I	Address Bit 5		58	RESET	I	Reset	HIGH
25	A ₄	I	Address Bit 4		59	WAIT#	O	Extend Bus Cycle	LOW
26	A ₃	I	Address Bit 3		60	RFU		Reserved	
27	A ₂	I	Address Bit 2		61	REG#	I	Attribute Memory Select	N.C.
28	A ₁	I	Address Bit 1		62	BVD ₂	O	Battery Voltage Detect 2	
29	A ₀	I	Address Bit 0	N.C.	63	BVD ₁	O	Battery Voltage Detect 1	
30	D ₀	I/O	Data Bit 0		64	D ₈	I/O	Data Bit 8	
31	D ₁	I/O	Data Bit 1		65	D ₉	I/O	Data Bit 9	
32	D ₂	I/O	Data Bit 2		66	D ₁₀	I/O	Data Bit 10	
33	WP	O	Write Protect	HIGH	67	CD ₂ #	O	Card Detect 2	LOW
34	GND		Ground		68	GND		Ground	

	OUTPUT	bus. D ₁₅ is the most significant bit.
CE ₁ #, CE ₂ #	INPUT	CARD ENABLE 1 & 2: CE ₁ # enables EVEN byte accesses on D ₀₋₇ , CE ₂ # enables ODD byte accesses on D ₈₋₁₅ . Cannot access Odd Bytes on D ₀₋₇ .
OE#	INPUT	OUTPUT ENABLE: Active low signal gating read data from the memory card.
WE#	INPUT	WRITE ENABLE: Active low signal gating write data to the memory card.
RDY/BSY#	OUTPUT	READY/BUSY OUTPUT: Indicates status of internally timed erase or write activities. A high output indicates the memory card is ready to accept accesses.
CD ₁ #, CD ₂ #	OUTPUT	CARD DETECT 1 & 2: These signals provide for card insertion detection. The signals are connected to ground internally on the memory card, and will be forced low whenever a card is placed in the socket. The host socket interface circuitry shall supply 10K or larger pull-up resistors on these signal pins.
WP	OUTPUT	WRITE PROTECT: Write Protect reflects the status of the Write Protect switch on the memory card. WP set to high = write protected.
V _{PP1} , V _{PP2}	N.C.	WRITE/ERASE POWER SUPPLY 1 & 2: These power signals are not connected for the single supply.
V _{CC}		CARD POWER SUPPLY: 3.3V or 5.0V for all internal circuitry.
GND		GROUND for all internal circuitry.
REG#	N.C.	REGISTER SELECT: The memory card has no separate attribute memory. REG# is unconnected on the card.
RESET	INPUT	RESET: Active high signal for placing card in Power-On Default State. RESET can be used as a POWER-DOWN signal for the memory array.
WAIT#	OUTPUT	WAIT: (Extended Bus Cycle) This signal is pulled high for compatibility.
BVD ₁ , BVD ₂	OUTPUT	BATTERY VOLTAGE DETECT 1 & 2: These signals are pulled high to maintain SRAM card compatibility.
VS ₁ #, VS ₂ #	OUTPUT	VOLTAGE SENSE 1 & 2: Notifies the host socket of the card's V _{CC} requirements. VS ₁ # is pulled down to ground and VS ₂ # is left open to indicate a 3.3V capable card has been inserted.
RFU		RESERVED FOR FUTURE USE
N.C.		NO INTERNAL CONNECTION TO CARD pin may be driven or left floating.

automatically resets to read array mode upon initial device power-up, or after reset. CE1#, CE2#, and OE# must be logically active to obtain 16 data bits at the outputs. The Card Enables (CE1# and CE2#) are used to select the addressed devices. Output Enable (OE#) is the data input/output (D0–D15) direction control, and when active, drives data from the selected memory onto the data bus. WE# must be driven to V_{IH} during a read access.

6. 1. 2 Output Disable

With OE# at a logic-high level (V_{IH}), the device outputs are disabled. Outputs (D0–D15) are placed in a high-impedance state.

6. 1. 3 Standby

CE1# and CE2# at a logic-high level (V_{IH}) places the card in standby mode. Standby operation disables much of the card's circuitry and substantially reduces device power consumption. The outputs (D0–D15) are placed in a high-impedance state independent of the status of OE#. If the host deselects the card during a write or erase, the card continues to function and consume normal active power until the operation completes.

6. 1. 4 Deep Power-Down

RESET at V_{IH} initiates the deep power-down mode.

During reads, an active RESET deselects the memory, places output drivers in a high-impedance state, and turns off all internal circuits. RESET must be held high for a minimum of 100 ns. After returning from deep power-down, the host must wait before initial memory access outputs are valid, as determined by t_{PHQV}. After this wake-up interval, the host can resume normal operations to the card. Card reset forces the CUI to reset to read array mode and sets the status register to 80H.

During block erase, byte write, or lock-bit configuration modes, an active RESET will abort the operation. RDY/BSY# remains low until the reset operation completes. Memory contents being altered are no longer valid; the data may be partially erased or written. The host must wait after RESET goes to logic-Low (V_{IL}) before it can write another command, as determined by t_{PHWL}.

It is important to assert RESET to the card during a system reset. If a CPU reset occurs without a card reset, the host will not be able to read from the card if that card is in a different mode when the system reset occurs.

For example, if an end-user initiates a host reset when the card is in read status register mode, the host will attempt to read code from the card, but will actually read status register data. Sharp's ID243 Series Flash Memory Card

F0000	Future Implementation	Block 15
	(Blocks 2 through 14)	
1FFFF	Reserved for Future Implementation	
10004		
10003		
10002	Block 1 Lock Configuration Code	
10001	Reserved for Future Implementation	
10000	Future Implementation	Block 1
0FFFF	Reserved for Future Implementation	
00004		
00003		
00002	Block 0 Lock Configuration Code	
00001	Device Code	
00000	Manufacture Code	Block 0

Figure 1. Device Identifier Code Memory Map

6. 1. 5 Read Identifier Codes Operation

The read identifier codes operation outputs the manufacturer code (Block 0), device code (Block 0), and block lock configuration codes (for each block), see Figure 1. Using the manufacturer and device codes, the system CPU can automatically match the device with its proper algorithms. The block lock codes identify locked and unlocked blocks.

6. 1. 6 CUI Writes

Writes to the CUI enable reading of device data and intelligent identifiers. They also control inspection and clearing of the Status Register. The contents of the interface register serves as input to the internal state machine on each component.

The CUI itself does not occupy an addressable memory location. The interface register is a latch used to store the command, address and data information needed to execute the command. Erase Setup and Erase Confirm commands require both appropriate command data and an address within the block to be erased. The Write Setup command requires both appropriate command data and the address of the location to be written, while the Write command consists of the data to be written and the address of the location to be written.

V_{CC} at 3.0 V provides the highest read performance. Internal device detection circuitry automatically configures the device.

7. Card Control Logic

7.1 Word Addressing

Sharp's ID243 Series Flash Memory Card uses two $\times 8$ devices in parallel to form the Memory card $\times 16$ data bus. If the host writes a command to the card, it must make sure that it writes the command to both devices in the card. For example, a component write command is 40H, so a card write command must be 4040H. This same procedure must be followed when reading from the status register. A component status register is only 8 bits and may return 80H when read. However, the card status register is 16 bits and may return 8080H.

7.2 Decode Logic

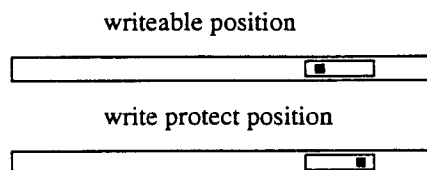
The decode logic enables the appropriate component device pair during a read or write access. Unused upper addresses for the ID243 Series Flash Memory Card will not be decoded. The address decoding will wrap around at the card's density.

7.3 Write Protect Switch

The ID243 Series Flash Memory Card has a write protect switch on the back of the card. When the switch is in the write protect position, the card blocks all writes to the card (see Figure 2).

NOTE

When the write protect switch is in the write protect position, all writes are disabled to the flash array including all commands to the CUI.



NOTE:

The write protect switch is represented by the solid black rectangle.

Figure 2. Write Protect Switch

Mode	RESET	CE ₂ #	CE ₁ #	OE#	WE#	A ₁	V _{PP}	D ₈₋₁₅	D ₀₋₇	RY/BY#	Notes
Even Byte-Read	V _{IL}	V _{IH}	V _{IL}	V _{IL}	V _{IH}	×	×	High-Z	Even	×	1.2.3
Odd Byte-Read	V _{IL}	V _{IL}	V _{IH}	V _{IL}	V _{IH}	×	×	Odd	High-Z	×	1.2.3
Word-Read	V _{IL}	V _{IL}	V _{IL}	V _{IL}	V _{IH}	×	×	Odd	Even	×	1.2.3
Even Byte-Write	V _{IL}	V _{IH}	V _{IL}	V _{IH}	V _{IL}	×	×	xxx	Even	V _{OL}	3.4
Odd Byte-Write	V _{IL}	V _{IL}	V _{IH}	V _{IH}	V _{IL}	×	×	Odd	xxx	V _{OL}	3.4
Word-Write	V _{IL}	V _{IL}	V _{IL}	V _{IH}	V _{IL}	×	×	Odd	Even	V _{OL}	3.4
Manufacturer ID	V _{IL}	V _{IL}	V _{IL}	V _{IL}	V _{IH}	V _{IL}	×	89H	89H	V _{OH}	—
Device ID	V _{IL}	V _{IL}	V _{IL}	V _{IL}	V _{IH}	V _{IH}	×	A6H	A6H	V _{OH}	5
Standby	V _{IL}	V _{IH}	V _{IH}	×	×	×	×	High-Z	High-Z	×	—
Output Disable	V _{IL}	×	×	V _{IH}	V _{IH}	×	×	High-Z	High-Z	×	—
Power-Down	V _{IH}	×	×	×	×	×	×	High-Z	High-Z	×	—

Table 1. Function Table

NOTES:

1. Refer to DC Characteristics.
2. × can be V_{IL} or V_{IH} for control pins and address.
3. RDY/BSY# is V_{OL} when the WSM is executing internal byte write or block erase algorithms. It is V_{OH} when the WSM is not busy, in erase suspend mode, or deep power-down mode.
4. Refer to Table 2 for valid D_N during a write operation.
5. The device code can be A6H or AAH. Software should check for all two cases for compatibility with future cards.

Command	Bus Cycles Req'd.	Notes	First Bus Cycle			Second Bus Cycle		
			Oper ⁽¹⁾	Addr ⁽²⁾	Data ⁽³⁾	Oper ⁽¹⁾	Addr ⁽²⁾	Data ⁽³⁾
Read Array/Reset	1	—	Write	×	FFFFH	—	—	—
Read Identifier Codes	≥2	4	Write	×	9090H	Read	IA	ID
Read Status Register	2	—	Write	×	7070H	Read	×	SRD
Clear Status Register	1	—	Write	×	5050H	—	—	—
Block Erase	2	—	Write	BA	2020H	Write	BA	D0D0H
Word Write	2	5	Write	WA	4040H or 1010H	Write	WA	WD
Block Erase and Word Write Suspend	1	—	Write	×	B0B0H	—	—	—
Block Erase and Word Write Resume	1	—	Write	×	D0D0H	—	—	—
Set Block Lock-Bit	2	—	Write	BA	6060H	Write	BA	0101H
Clear Block Lock-Bits	2	—	Write	×	6060H	Write	×	D0D0H

NOTES:

1. Bus operations are defined in Table 1.
2. × = Any valid address within the device.
IA = Identifier Code Address: see Figure 1.
BA = Address within the block being erased or locked.
WA = Address of memory location to be written.
3. SRD = Data read from status register. See Table 4 for a description of the status register bits.
WD = Data to be written at location WA. Data is latched on the rising edge of WE# or CE# (Whichever goes high first).
ID = Data read from identifier codes.
4. Following the Read Identifier Codes command, read operations access manufacturer, device and block lock configuration codes. See Section 8.2 for read identifier code data.
5. Either 40H or 10H are recognized by the WSM as the byte write setup.
6. Commands other than those shown above are reserved for future device implementations and should not be used.

The host initiates the identifier code operation by writing the Read Identifier Codes command. Following the command write, read cycles from addresses shown in Figure 1 retrieve the manufacturer, device and block lock configuration codes (see Table 3 for identifier code data). To terminate the operation, write another valid command. Although Table 3 lists the device code as A6A6, this family of Sharp's ID243 Series Flash Memory Card could also have device codes AAAA. Host software should check for all two cases for compatibility with future cards.

Table 3. Identifier Codes

Code	Address	Data ⁽²⁾
Manufacture Code	00000	8989
Device Code	00001	A6A6
Block Lock Configuration	× 0002 ⁽¹⁾	
• Block is Unlocked		D _{0,8} = 0
• Block is Locked		D _{0,8} = 1
• Reserved for Future Use		D _{1-7,9-15}

NOTES:

1. × selects the specific block lock configuration code to be read.
See Figure 1 for the device identifier code memory map.
2. The addresses listed are word addresses and store 16 bits of data.

8.3 Read Status Register Command

The LH28F008SC components on the ID243 Series Flash Memory Card each contain a Status Register which may be read to determine when a write, block erase, or lock bit configuration is complete, and whether that operation completed successfully (see Table 4). The host may read the Status Register at any time by writing the Read Status Register command to the CUI. After writing this command, all subsequent read operations output data from the Status Register, until the host writes another valid command to the CUI. The flash components latch the contents of the Status Register on the falling edge of OE# or CE#, whichever occurs first. OE# or CE# must be toggled to V_{IH} before further reads to update the Status Register latch.

NOTE:

The ID243 Series Flash Memory Card arranges two LH28F008SC devices in parallel to from a ×16 bus. Both status registers need to be checked when determining the status of a ×16 erase/write operation.

NOTE:

If V_{PP} has not been turned on, the WSM sets the V_{PP} status bit. However, the ID243 Series Flash Memory Card ties V_{PP} and V_{CC} on the LH28F008SC devices together so if V_{CC} is on then V_{PP} will also be on. If for some reason the WSM sets the V_{PP} Status bit, the host must clear the status register before it attempts further writes or block erases.

8.5 Block Erase Command

The host executes an erase command one block at a time using a two-cycle command. The host writes a block erase setup command first, followed by a block erase confirm command. These two commands require appropriate sequencing and an address within the block to complete (erase changes all block data to FFH). The WSM handles block preconditioning, erase, and verify internally (invisible to the system). After the host writes the two-cycle block erase sequence, the device automatically outputs status register data when read. The CPU can detect block erase completion by analyzing the output data of the RDY/BSY# signal or status register bit SR.7.

When the block erase completes, status register bit SR.5 should be checked. If a block erase error is detected, the host should clear the status register before system software attempts corrective actions. The CUI remains in read status register mode until the host issues a new command.

This two-step command sequence of set-up followed by execution ensures that block contents are not accidentally erased. An invalid Block Erase command sequence will result in the WSM setting status register bits SR.4 and SR.5 to "1". Successful block erase requires that the corresponding block lock-bits is not set. If the host attempts a block erase when the corresponding block lock-bit is set, the WSM will set SR.1 and SR.5 to "1".

8.6 Word Write Command

The host executes a word write by a two-cycle command sequence. The host writes word write setup (standard 4040H or alternate 1010H) first, followed by a second write that specifies the address and data (latched on the rising edge of WE#). The WSM then takes over, controlling the word write and write verify algorithms internally. After the host writes the word write sequence, the device automatically output status register data when read. The CPU can detect the completion of the byte write event by analyzing the RDY/BSY# pin or status register bit SR.7.

When the WSM completes the word writes, the host should check status register bit SR.4. If the host detects a write error, it should clear the status register. The internal WSM verify only detects errors for "1"s that do not

suspend the block erase sequence at a predetermined point in the algorithm. After the host writes the Block Erase Suspend command, the host should then write the Read Status Register command. Polling status register bits SR.7 and SR.6 can determine when the WSM suspends the block erase operation (both will be set to "1"). RDY/BSY# will also transition to V_{OH} . Specification t_{WHRH2} defines the block erase suspend latency. It is also possible that the block erase completes before the device has an opportunity to suspend. The host should also check for this condition.

After the block erase has been suspended, the host can issue a read array command or a word write command to any block except the one that has been suspended. Using the Word Write Suspend command (see Section 8.8), a word write operation can also be suspended. During a word write operation with block erase suspended, status register bit SR.7 will return to "0" and the RDY/BSY# output will transition to V_{OL} . However, SR.6 will remain "1" to indicate block erase suspend status. The only other valid commands while block erase is suspended are Read Status Register and Block Erase Resume. After the host writes a Block Erase Resume command to the flash memory, the WSM will continue the block erase process. Status register bits SR.6 and SR.7 will automatically clear and RDY/BSY# will return to V_{OL} . After the host writes the Erase Resume command, the device automatically outputs status register data when read. Block erase cannot resume until word write operation initiated during block erase suspend have completed.

8.8 Word Write Suspend Command

The Word Write Suspend command allows word write interruption to read data in other flash memory locations. Once the word write process starts, writing the Word Write Suspend command requests that the WSM suspend the word write sequence at a predetermined point in the algorithm. After the host writes the Word Write Suspend command, it should write the Read Status Register command. Polling status register bits SR.7 and SR.2 can determine when the WSM suspends the byte write operation (both will be set to "1"). RDY/BSY# will also transition to V_{OH} . Specification t_{WHRH1} defines the word write suspend latency. It is also possible that the word write completes before the device has an opportunity to suspend. The host should also check for this condition.

After the word write has been suspended, the host can write the Read Array command to read data from any location except the suspended location. The only other valid commands while word write is suspended are Read Status Register and Word Write Resume. After the host writes a Word Write Resume to the CUI, the WSM will continue the word write process. Status register bits SR.2 and SR.7 will automatically clear and RDY/BSY# will return to V_{OL} . After the host writes the Word Write Resume command, the device automatically outputs status register data when read.

After the host completes the command sequence, the card automatically outputs status register data when read. The CPU can detect the completion of the set lock-bit event by analyzing the RDY/BSY# pin output or status register bit SR.7.

When the WSM completes the set lock-bit operation, the host should check status register bit SR.4. If the host detects an error it should clear the status register. The CUI will remain in read status register mode until the host issues a new command.

This two-step sequence of set-up followed by execution ensures that the host does not accidentally set the lock-bits. An invalid Set Block Lock-Bit command will result in the WSM setting status register bits SR.4 and SR.5 to "1".

8.10 Clear Block Lock-Bits Command

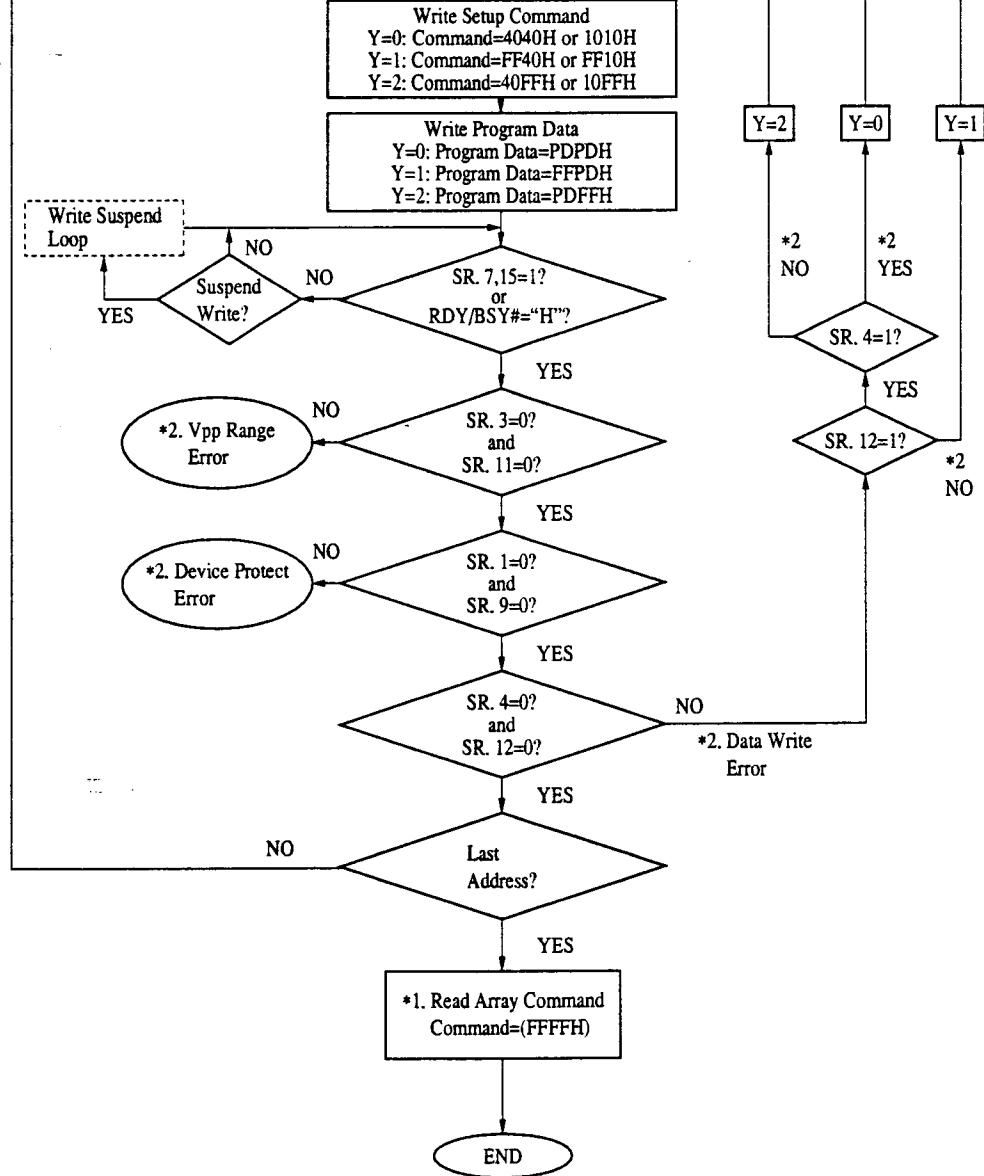
The host clears all set block lock-bits in parallel using the Clear Block Lock-Bits command. The host is free to clear block lock-bits using the Clear Block Lock-Bits command.

The host executes the clear block lock-bits operation using a two-cycle command sequence. The host must first issue a Clear Block Lock-Bits setup command. This command is followed by a confirm command. After the host completes the two-cycle command sequence, the device automatically outputs status register data when read. The CPU can detect completion of the clear block lock-bits event by analyzing the RDY/BSY# pin output or status register bit SR.7.

When the WSM completes the operation, the host should check status register bit SR.5. If the host detects a clear block lock-bit error, the host should clear the status register. The CUI will remain in read status register mode until the host issues another command.

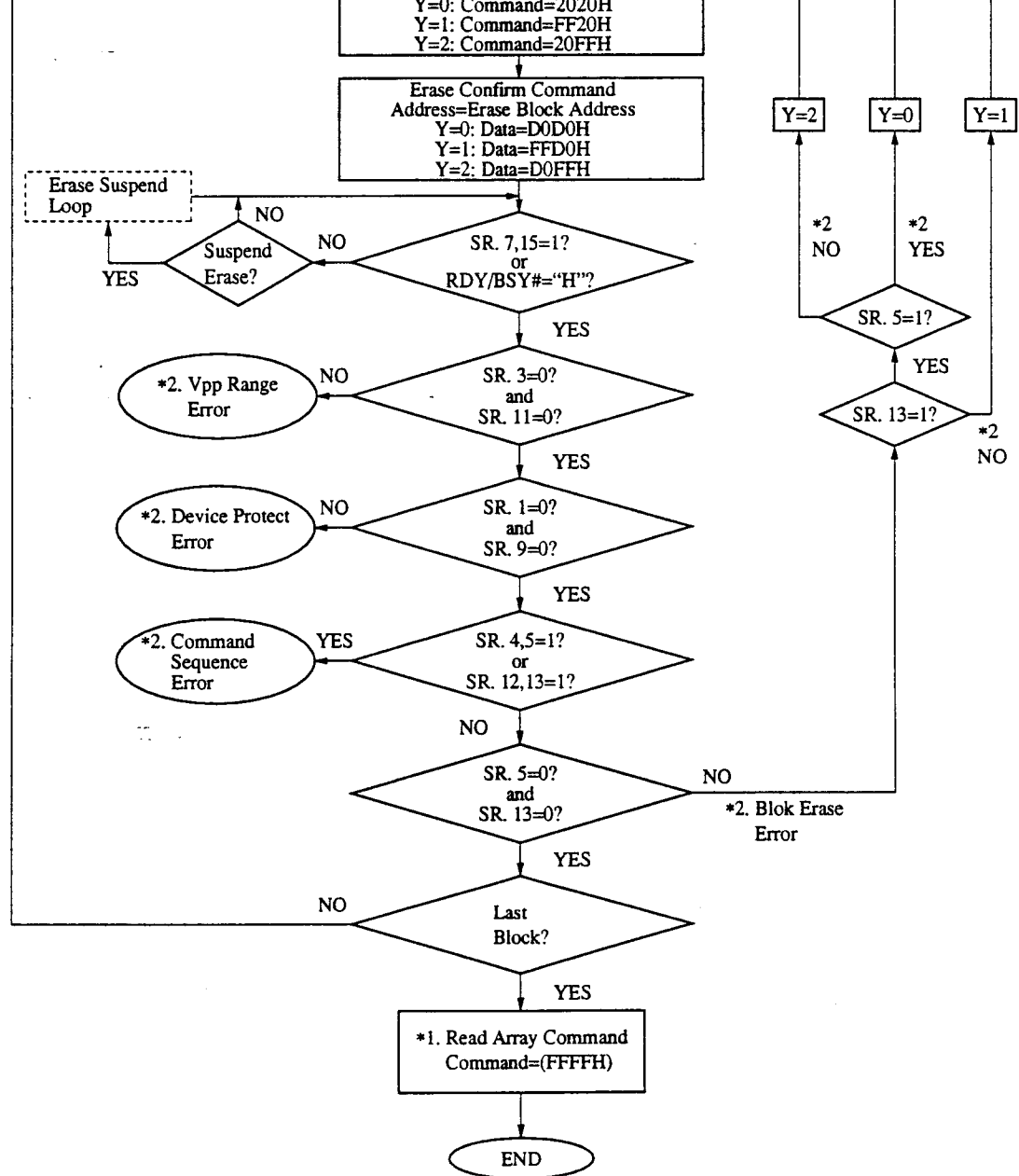
This two-step sequence of set-up followed by execution ensures that the host does not accidentally clear block lock-bits. An invalid Clear Block Lock-Bits command sequence will result in the WSM setting status register bits SR.4 and SR.5 to "1".

If a clear block lock-bits operation is aborted due to V_{CC} transitioning out of valid range or RESET active transition, block lock-bit values are left in an undetermined state. The host must repeat the clear block lock-bits command to initialize block lock-bit contents to known values.



Note) *1. Write FFFFH after the last word write operation to reset the device to Read Array Mode.

*2. If error is detected, clear the Status Register before attempting retry or other error recovery.



Note) *1. Write FFFFH after the last block erase operation to reset the device to Read Array Mode.

*2. If error is detected, clear the Status Register before attempting retry or other error recovery.

NOTES:

1. Operating temperature is for commercial product defined by this specification.
2. All specified voltages are with respect to GND.
3. Output shorted for no more than one second. No more than one output shorted at a time.

9.2 Recommended Operating Conditions

PARAMETER	SYMBOL	MINIMUM	MAXMUM	UNIT
Operating Temperature	T _{OPR}	0	60	°C
Supply Voltage 1	V _{CC1}	3.0	3.6	V
Supply Voltage 2	V _{CC2}	4.75	5.25	V

9.3 CapacitanceT_a = 25°C, f = 1MHz

PARAMETER	SYMBOL	MIN	TYP	MAX	UNIT	CONDITION
Input Capacitance	C _{IN}	—	24	32	pF	V _{IN} = 0.0V
Input/Output Capacitance	C _{IO}	—	16	24	pF	V _{OUT} = 0.0V

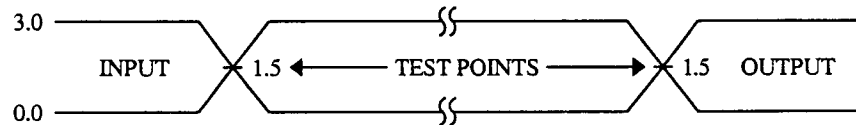
9.4 AC Input/Output Test Conditions

Figure 5. Transient Input/Output Reference Waveform for V_{CC} = 3.3V ± 0.3V and V_{CC} = 5.0V ± 5%
(Standard Testing Configuration)

AC test inputs are driven at 3.0V for a Logic "1" and 0.0V for a Logic "0". Input timing begins, and output timing ends, at 1.5V. Input rise and fall times (10% to 90%) < 10ns.

Input Leakage Current (OE#)	I _{LI4}	1	—45	2	—65	4	μ A	V _{CC} = V _{CC} Max, V _{IN} = V _{CC} or GND
Output Leakage Current (D0–D15)	I _{LO}	1	—	±1	—	±20	μ A	V _{CC} = V _{CC} Max, V _{IN} = V _{CC} or GND
V _{CC} Standby Current	I _{CCS}	1, 3	—	590	—	590	μ A	V _{CC} = V _{CC} Max, CE1#, CE2# = V _{CC} ± 0.2V, RESET = GND ± 0.2V
V _{CC} Deep Power-Down Current	I _{CCD}	1, 3	—	200	—	215	μ A	RESET = V _{CC} ± 0.2V, I _{OUT} (RDY/BSY#)=0 mA
V _{CC} Read Current	I _{CCR}	1, 3, 4, 5	—	25	—	75	mA	V _{CC} = V _{CC} Max, CE1#, CE2# = GND ± 0.2V, t _{cycle} = 150ns@3.3V, t _{cycle} = 100ns@5.0V, I _{OUT} = 0mA
V _{CC} Word Write or Set Lock-Bit Current	I _{CCW}	1, 5	—	115	—	150	mA	
V _{CC} Block Erase or Clear Lock-Bit Current	I _{CCE}	1, 5	—	75	—	100	mA	
V _{CC} Word Write or Block Erase Suspend Current	I _{CCWS} I _{CCES}	1, 2, 5	—	12	—	20	mA	CE1# = CE2# = V _{IH}

PARAMETER	SYMBOL	NOTES	V _{CC} = 3.3V		V _{CC} = 5.0V		UNIT	TEST CONDITIONS
			MIN	MAX	MIN	MAX		
Input Low Voltage	V _{IL}		0	0.8	0	0.8	V	
Input High Voltage	V _{IH}		0.7 V _{CC}	V _{CC}	0.7 V _{CC}	V _{CC}	V	
Output Low Voltage	V _{OL}		—	0.4	—	0.45	V	V _{CC} = V _{CC} Min, I _{OL} = 4mA@5.0V, I _{OL} = 2mA@3.3V
Output High Voltage	V _{OH}		V _{CC} - 0.4	—	V _{CC} - 0.4	—	V	V _{CC} = V _{CC} Min I _{OH} = -100 μ A
V _{CC} Lockout Voltage	V _{LKO}		2.0	—	2.0	—	V	

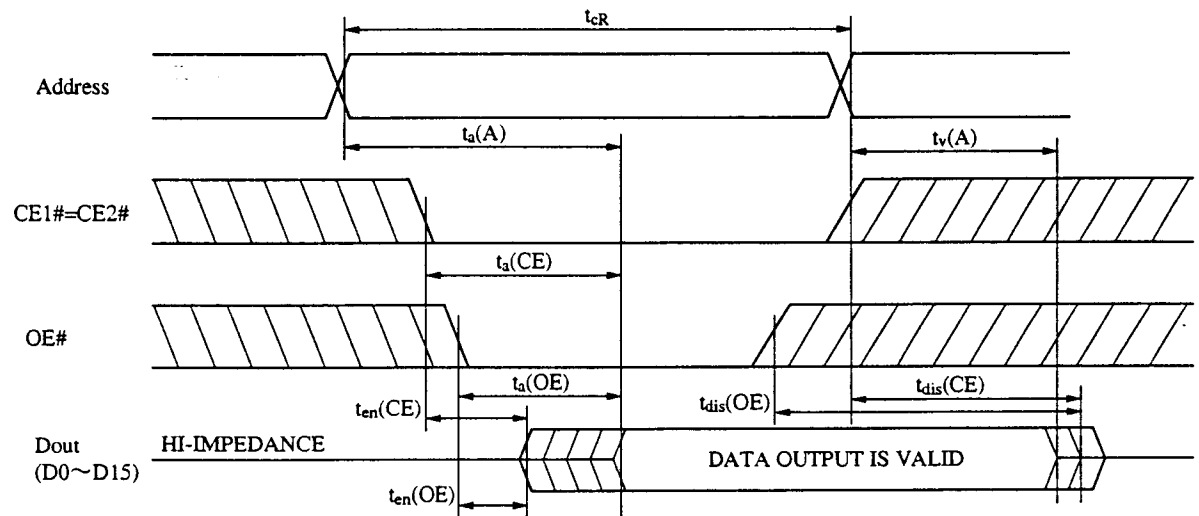
NOTES:

1. All currents are in RMS unless otherwise noted.
2. I_{CCWS} and I_{CCES} are specified with the device de-selected. If read or byte written while in erase suspend mode, the device's current draw is the sum of I_{CCWS} or I_{CCES} and I_{CCR} or I_{CCW}, respectively.
3. CMOS inputs are either V_{CC} ± 0.2V or GND ± 0.2V.
4. Automatic Power Savings (APS) reduces typical I_{CCR} to 2mA at 5V V_{CC} and 6 mA at 3.3V V_{CC} in static operation (addresses not switching).
5. All values are based on word accesses. Values for byte accesses are 50% of the specification listed.

PARAMETER	SYMBOL		V _{CC} = 3.3V		V _{CC} = 5.0V		UNIT
	IEEE	PCMCIA	MIN	MAX	MIN	MAX	
Read Cycle Time	t_{AVAV}	t_{cR}	150	—	100	—	ns
Address Access Time	t_{AVQV}	$t_a(A)$	—	150	—	100	
Card Enable Access Time	t_{ELQV}	$t_a(CE)$	—	150	—	100	
Output Enable Access Time	t_{GLQV}	$t_a(OE)$	—	75	—	50	
Output Disable Time from CE#*	t_{EHQV}	$t_{dis}(CE)$	—	75	—	50	
Output Disable Time from OE#*	t_{GHQZ}	$t_{dis}(OE)$	—	75	—	50	
Output Enable Time from CE#	t_{ELQNZ}	$t_{en}(CE)$	5	—	5	—	
Output Enable Time from OE#	t_{GLQNZ}	$t_{en}(OE)$	5	—	5	—	
Data Valid from Address Change	t_{AXQX}	$t_v(A)$	0	—	0	—	
Power-Down Recovery to Output Delay	t_{PHQV}		—	800	—	530	

* Time until output becomes floating. (The output voltage is not defined.)

11.2 AC Waveforms for Read Operations



- Note) 1. $WE\#$ = "HIGH", during a read cycle.
 2. Either "HIGH" or "LOW" in diagonal areas.
 3. The output data becomes valid when last interval, $t_a(A)$, $t_a(CE)$ or $t_a(OE)$ have concluded.

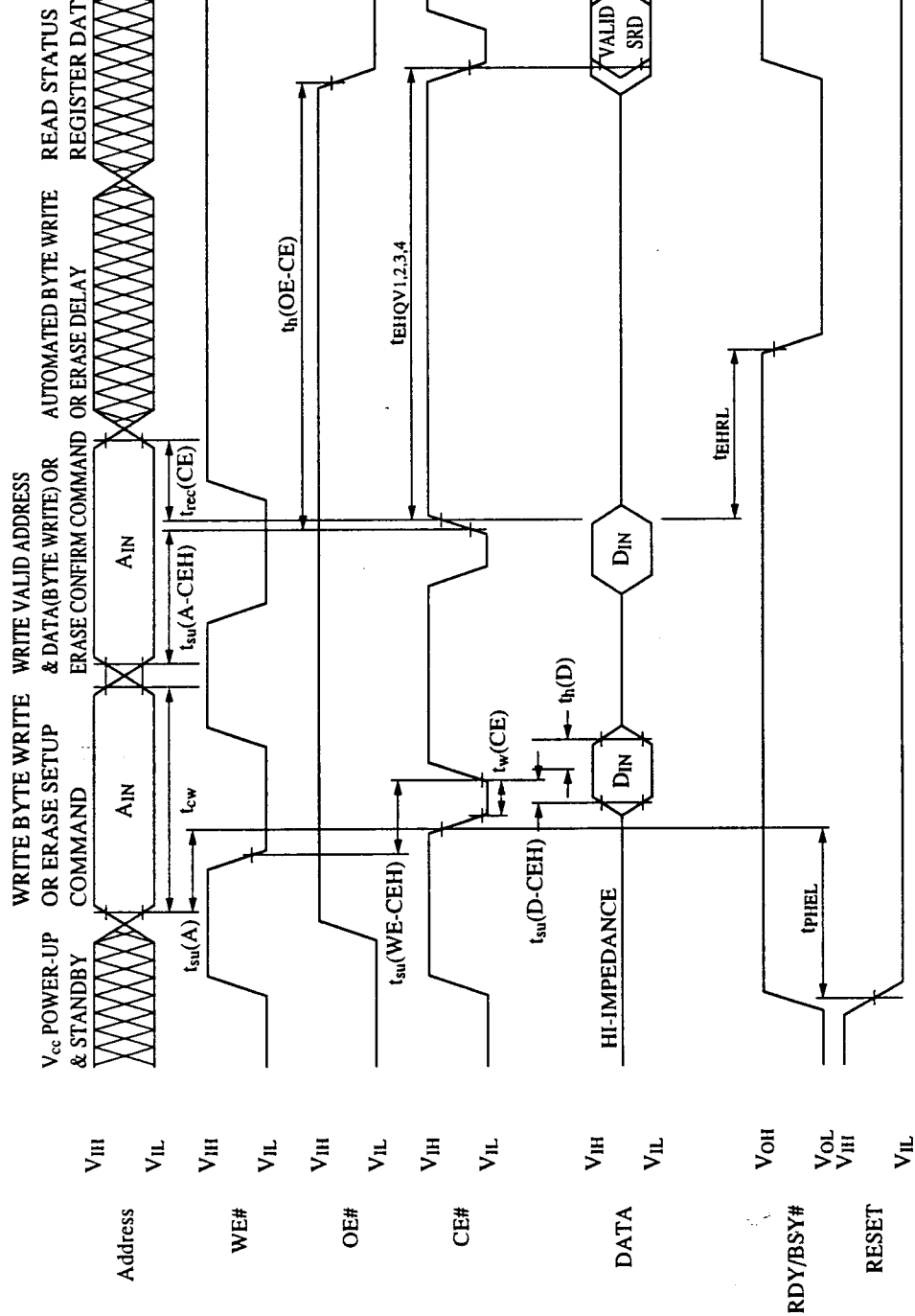
Data Setup Time for WE#	t _{DVWH}	t _{su} (D-WEH)	50	—	70	—	ns
Data Hold Time	t _{WHDX}	t _h (D)	20	—	15	—	
Output Enable Hold from WE#	t _{WHGL}	t _h (OE-WE)	10	—	10	—	
Card Enable Setup time for WE#	t _{ELWH}	t _{su} (CE-WEH)	100	—	70	—	
Address Setup for WE#	t _{AVWH}	t _{su} (A-WEH)	100	—	70	—	
Write Pulse Width	t _{WLWH}	t _w (WE)	80	—	60	—	
WE# High to RDY/BSY# Going Low	t _{WHRL}		—	300	—	150	μs
Power-Down Recovery to WE# Going Low	t _{PHWL}		1	—	1	—	

11.3.2 CE# Controlled Write Operations

(Ta = 0~60°C)

PARAMETER	SYMBOL		V _{CC} = 3.3V		V _{CC} = 5.0V		UNIT
	IEEE	PCMCIA	MIN	MAX	MIN	MAX	
Write Cycle Time	t _{AVAV}	t _{cw}	150	—	100	—	ns
Address Setup Time	t _{AVEL}	t _{su} (A)	20	—	10	—	
Write Recovery Time	t _{EHAX}	t _{rec} (CE)	20	—	15	—	
Data Setup Time for CE#	t _{DVEH}	t _{su} (D-CEH)	50	—	40	—	
Data Hold Time	t _{EHDX}	t _h (D)	20	—	15	—	
Output Enable Hold from CE#	t _{EHGL}	t _h (OE-CE)	10	—	10	—	
Write Enable Setup time for CE#	t _{WLEH}	t _{su} (WE-CEH)	100	—	70	—	
Address Setup for CE#	t _{AVEH}	t _{su} (A-CEH)	100	—	70	—	
Card Enable Pulse Width	t _{ELEH}	t _w (CE)	80	—	60	—	
CE# High to RDY/BSY# Going Low	t _{EHRL}		—	300	—	150	μs
Power-Down Recovery to CE# Going Low	t _{PHEL}		1	—	1	—	

11.3.4 AC Waveforms for Write Operations (CE# Controlled)



Note) While the data signal is in output mode, do not apply an opposite phase input signal.

Set Lock-Bit Time	t _{WHQV3} t _{EHQV3}	2	18	21	—	9.5	12	—	μs
Clear Block Lock-Bits Time	t _{WHQV4} t _{EHQV4}	2	1.5	1.8	—	0.9	1.1	—	s
Byte Write Suspend Latency Time to Read	t _{WHRH1} t _{EHRH1}	—	—	6	7	—	5	6	μs
Erase Suspend Latency Time to Read	t _{WHRH2} t _{EHRH2}	—	—	16.2	20	—	9.6	12	μs

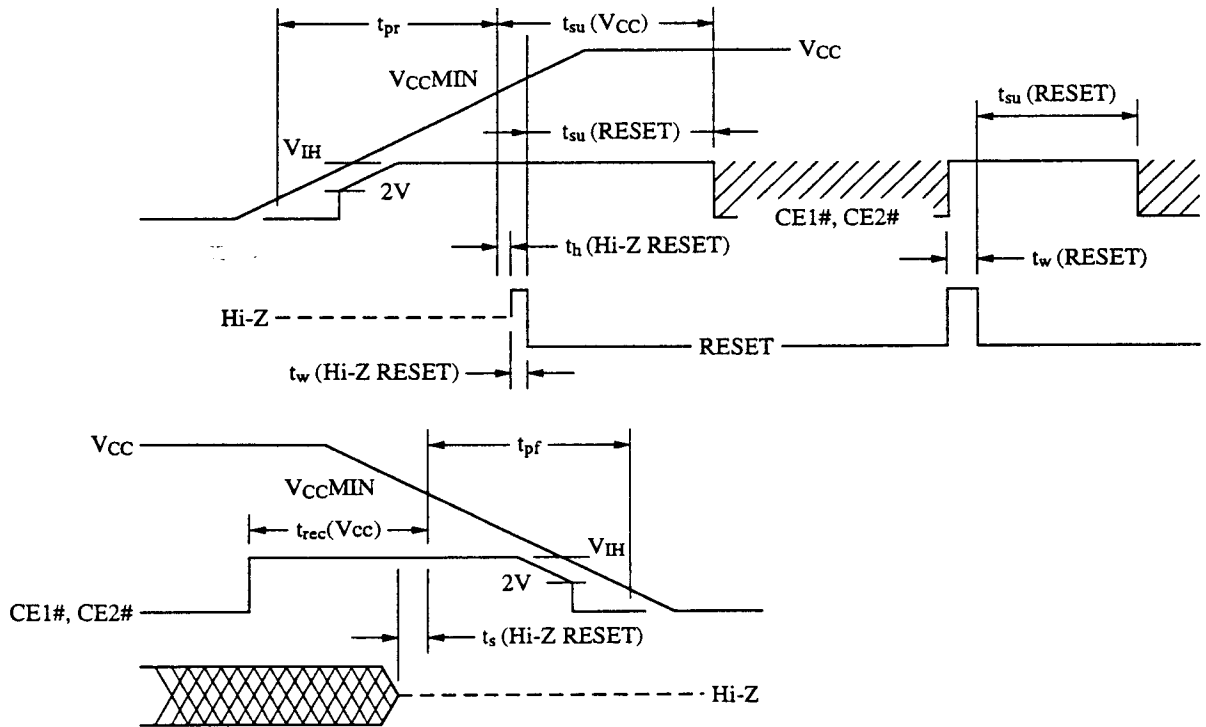
NOTES:

1. Typical values measured at Ta = 25°C and nominal voltages. Assumes corresponding lock-bits are not set.
Subject to change based on device characterization.
2. Excludes system-level overhead.
3. Sampled but not 100% tested.

CE# Recover Time	$t_{rec}(V_{CC})$	—	1.0	—	μs
V_{CC} Rising Time	t_{pr}	2	0.1	300	ms
V_{CC} Falling Time	t_{pf}	2	3.0	300	ms
RESET Width	$t_w(\text{RESET})$	—	10	—	μs
RESET Width	$t_h(\text{Hi-Z RESET})$	—	1	—	ms
RESET Width	$t_s(\text{Hi-Z RESET})$	—	0	—	ms

NOTES:

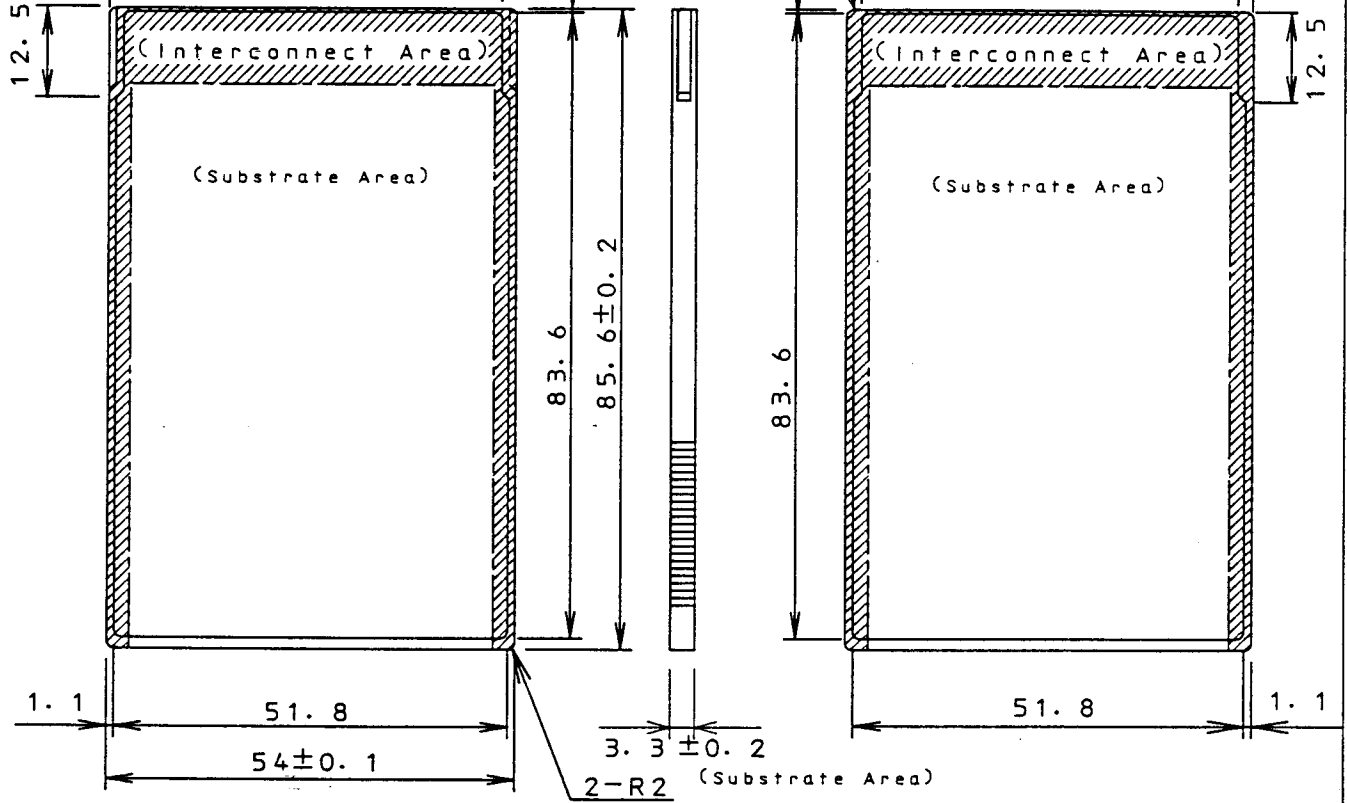
1. V_{iMAX} means Absolute Maximum Voltage for input in the period of $0.0V < V_{CC} < 2.0V$, $V_i(\text{CE\#})$ is only $0.00V - V_{iMAX}$
2. The t_{pr} and t_{pf} are defined as "linear waveforms" in the period of 10% to 90%, or vice-versa. Even if the waveform is not a "linear waveform," its rising and falling time must meet this specification.



Power-Up/Down Timing for Systems Supporting RESET

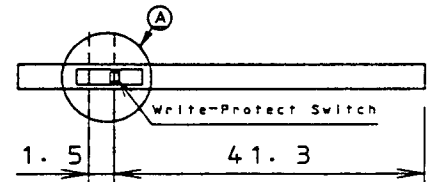
memory card.

- Avoid allowing the memory card connectors to come in contact with metals and avoid touching the connectors, as the internal circuits can be damaged by static electricity.
- Avoid storing in direct sunlight, high temperatures (do not place near heaters or radiators), high humidity and dusty areas.
- Avoid subjecting the memory card to strong physical abuse. Dropping, bending, smashing or throwing the card can result in loss of function.
- When the memory card is not being used, return it to its protective case.
- Do not allow the memory card to come in contact with fire.



FRONT

BACK



APPLICABLE		SCALE		UNIT			
		1 / 1		mm			
THICKNESS		MATERIAL		FINISH		CH. DATE	REVISE
						NAME	CHARGE
DATE		1996. 10. 09				MEMORY CARD	
DESIGN		DRAW		TRACE		CHECK	
						EXTERNAL DIAGRAM	
						PCMCIA Rel. 2.0 TYPE1	
						DRAWING NO.	
						IMC066-A100	



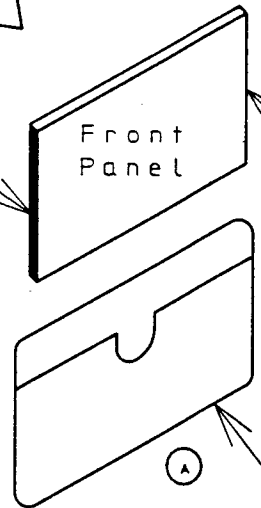
Note 4

- 5. The outer carton
- 6. The product name are either written on the label which
- 7. The outer carton contains 4 outer
- 8. The product name are either written on the label which is

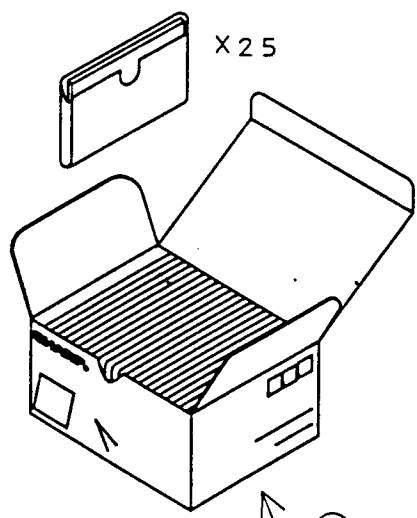
Connector Side

Front Panel

IC Memory Card

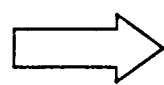


Flexible Plastic Case

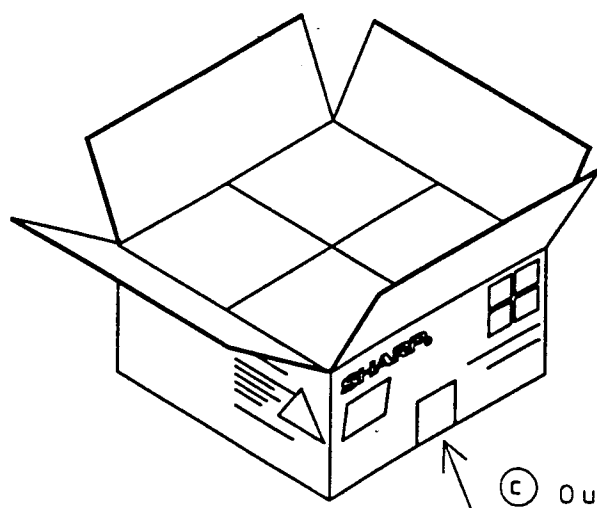


X25

(B) Inner Carton
(25 pieces contained)



X4

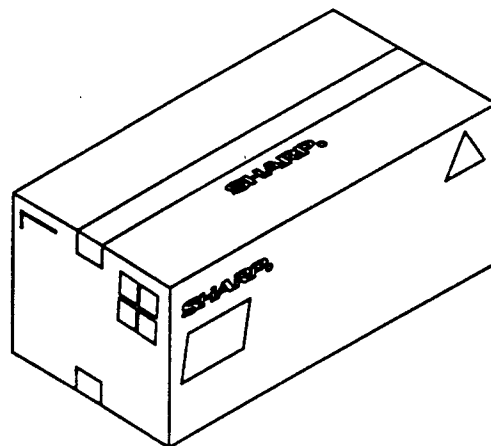
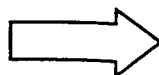
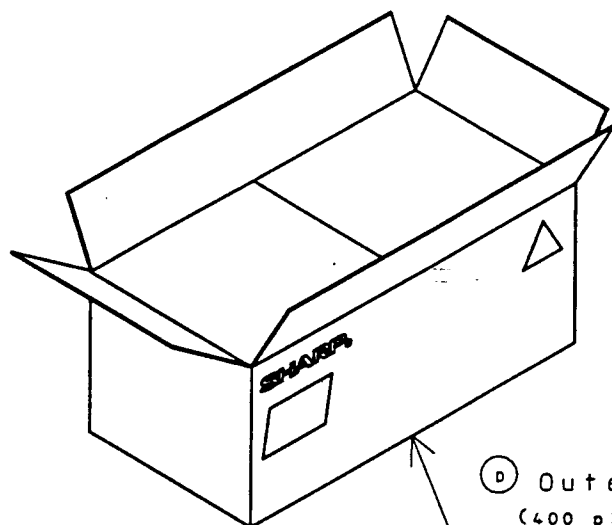
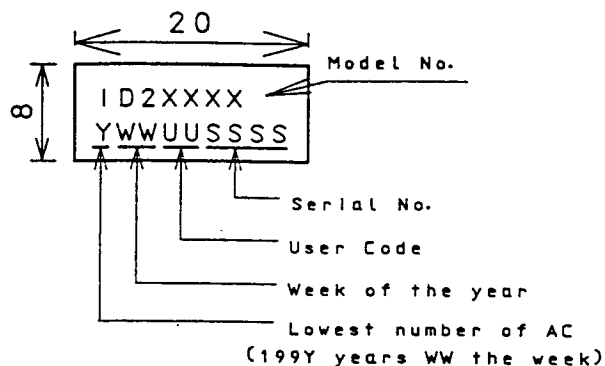


(C) Outer Carton
(100 pieces contained)

Product name, lot no. (product no.), quantity and the date
 her written directly on the outer carton, or printed
 label which is then attached on the outer carton.

er carton is then put in the outer case, which
 as 4 outer cartons. (Note 3.)

Product name, Lot no. (product no.), quantity and the date
 her written directly on the case or printed on the
 which is then attached on the case.



① Outer Case
 (400 pieces contained)



er Carton
 (pieces contained)

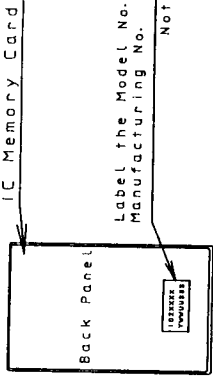
APPLICABLE MODEL		SCALE		UNIT		A		
	1D243XXX			mm		A		
THICKNESS	DEFFERENCE	MATERIAL	FINISH		CH. DATE	REVISE		CHARGE
					NAME	1D243XXX Packing Specification		
DATE		1996. 12. 25						
K. Doshi S. Sasaki S. Shintani		MEMORY CARD BUSINESS PROJECT TEAM						
		INTEGRATED CIRCUITS GROUP						
		SHARP CORPORATION						
		DRAWING NO.				1MC073-J300		

SHARP

ID243XXX

15. Packing Specification

Connector Side

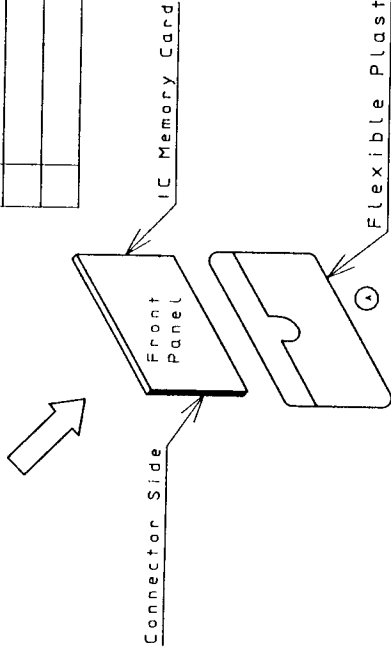


Parts List

Parts Name	
A Flexible Plastic Case	
B Inner Carton (25 pieces contained)	
C Outer Carton (100 pieces contained)	
D Outer Case (400 pieces contained)	

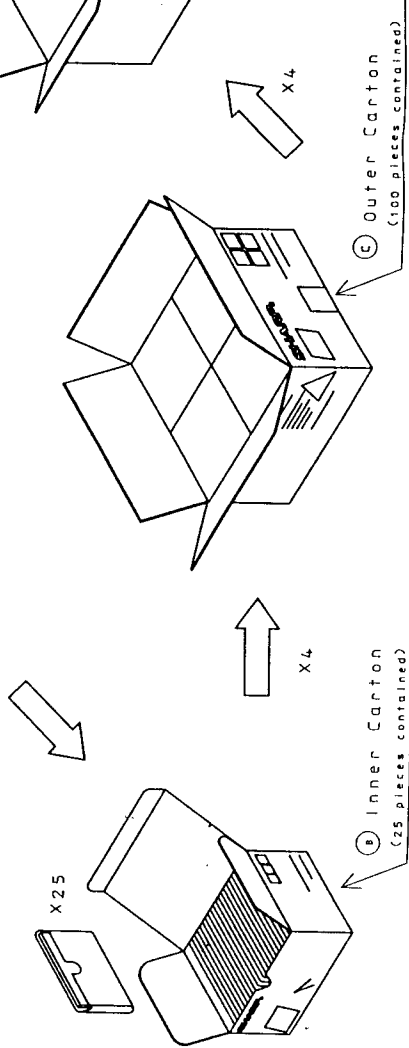
Label the Model No. and Manufacturing No.

Note 4



Packing Specification

1. Label the Model No. and Manufacturing No. on the back panel of the card.
2. Each memory card is contained in the flexible plastic case. (The front side of the card comes to the place where it is released, and the connector side is placed against the point, so that the connector is not touched by finger. (See the figure.))
3. The inner carton contains 25 pieces of the card with case. (Note 1.)
4. The product name, Lot No. (product no.), quantity and are either written directly on the inner carton, or printed on the label which is then attached on inner carton.
5. The outer carton contains 4 inner cartons. (Note 2.)
6. The product name, Lot No. (product no.), quantity and are either written directly on the outer carton, or printed on the label which is then attached on the outer carton.
7. The outer carton is then put in the outer case, which contains 4 outer cartons. (Note 3.)
8. The product name, Lot No. (product no.), quantity and are either written directly on the case or printed on the label which is then attached on the case.



APPLICABLE	
MODEL	ID243X
THICKNESS	DEFERRED
DATE	1996.12
Signature	158

FLASH MEMORY FLASH NON-VOLATILE MEMORY FLASH E2ROM FLASH ROM
READ ONLY MEMORY ETOX ID243E01 4M PC Card conforms to PCMCIA Rel. 2.0